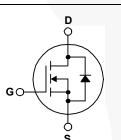


N-Channel QFET[®] MOSFET 150 V, 50 A, 42 mΩ

Features

- + 50 A, 150 V, ${\sf R}_{{\sf DS}({\sf on})}$ = 42 m Ω (Max) @V_{{\sf GS}} = 10 V, I_D = 25 A
- Low Gate Charge (Typ. 85 nC)
- Low Crss (Typ. 100 pF)
- 100% Avalanche Tested
- 175°C Maximum Junction Temperature Rating



control, and variable switching power applications.

This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor's proprietary planar

stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state

resistance, and to provide superior switching performance and

high avalanche energy strength. These devices are suitable for

switched mode power supplies, audio amplifier, DC motor

Description

Absolute Maximum Ratings T_C = 25°C unless otherwise noted.

Symbol	Parameter		FQA46N15	Unit	
V _{DSS}	Drain-Source Voltage		150	V	
I _D	Drain Current - Continuous ($T_c = 25^{\circ}C$)		50	А	
	- Continuous (T _C = 100°C)		35.3	А	
DM	Drain Current - Pulsed	(Note 1)	200	А	
V _{GSS}	Gate-Source Voltage		± 25	V	
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	650	mJ	
AR	Avalanche Current	(Note 1)	50	A	
E _{AR}	Repetitive Avalanche Energy	(Note 1)	25	mJ	
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	6.0	V/ns	
P _D	Power Dissipation ($T_C = 25^{\circ}C$)		250	W	
	- Derate above 25°C		1.67	W/°C	
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +175	°C	
TL	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 Seconds		300	°C	

TO-3PN

Thermal Characteristics

Symbol	Parameter	FQA46N15	Unit
$R_{ ext{ heta}JC}$	Thermal Resistance, Junction-to-Case, Max.	0.6	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink, Typ.	0.24	°C/W
$R_{ extsf{ heta}JA}$	Thermal Resistance, Junction-to-Ambient, Max.	40	°C/W

Package	Marking	and	Ordering	Information
i uonugo	manning	ana	Craoring	mornation

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantity
FQA46N15	FQA46N15	TO-3PN	Tube	N/A	N/A	30 units

Electrical Characteristics T_C = 25°C unless otherwise noted.

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
Off Charac	teristics					
BV _{DSS}	Drain-Source Breakdown Voltage	V_{GS} = 0 V, I _D = 250 μ A	150			V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Coefficient	$I_D = 250 \ \mu A$, Referenced to 25°C		0.16		V/°C
I _{DSS} Zer	Zero Gate Voltage Drain Current	V _{DS} = 150 V, V _{GS} = 0 V			1	μA
		V _{DS} = 120 V, T _C = 150°C			10	μA
I _{GSSF}	Gate-Body Leakage Current, Forward	V_{GS} = 25 V, V_{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V_{GS} = -25 V, V_{DS} = 0 V			-100	nA
On Charact	teristics					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \ \mu A$	2.0		4.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = 10 V, I _D = 25A		0.033	0.042	Ω
9 _{FS}	Forward Transconductance	V _{DS} = 40 V, I _D = 25A		36		S
Dynamic Cl	haracteristics					
C _{iss}	Input Capacitance	V _{DS} = 25 V, V _{GS} = 0 V,		2500	3250	pF
C _{oss}	Output Capacitance	f = 1.0 MHz		520	670	pF
C _{rss}	Reverse Transfer Capacitance			100	130	pF
Switching C	Characteristics					
t _{d(on)}	Turn-On Delay Time	V _{DD} = 75 V, I _D = 45.6A,		35	80	ns
t _r	Turn-On Rise Time	- R _G = 25 Ω 		320	650	ns
t _{d(off)}	Turn-Off Delay Time			210	430	ns
t _f	Turn-Off Fall Time	(Note 4)		200	410	ns
Qg	Total Gate Charge	V _{DS} = 120 V, I _D = 45.6A,		85	110	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V		15		nC
Q _{gd}	Gate-Drain Charge	(Note 4)	-	41		nC
Drain-Source	ce Diode Characteristics and Maximum Ratings	3			/	
I _S	Maximum Continuous Drain-Source Diode Forward Current				50	Α
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current				200	А
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S =50A			1.5	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _S = 45.6 A,		130		ns
Q _{rr}	Reverse Recovery Charge	dI _F / dt = 100 A/μs		0.55		μC

NOTES:

1. Repetitive rating: pulse-width limited by maximum junction temperature.

2. L = 0.43 mH, I_{AS} = 50 A, V_{DD} = 25 V, R_G = 25 $\Omega,$ starting T_J = 25°C.

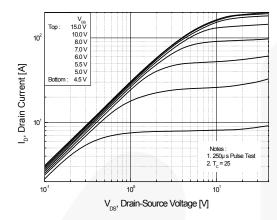
 $3.I_{SD} \leq 46.6$ A, di/dt ≤ 300 A/µs, $V_{DD} \leq BV_{DSS},$ starting T_J = 25°C.

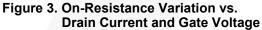
4. Essentially independent of operating temperature typical characteristics.

Typical Performance Characteristics



Figure 2. Transfer Characteristics





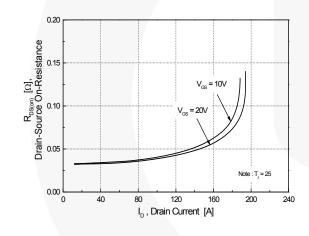
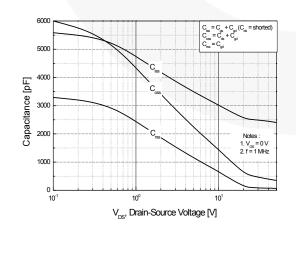
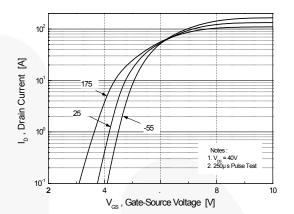
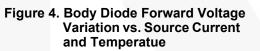
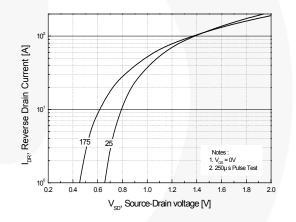


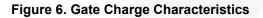
Figure 5. Capacitance Characteristics

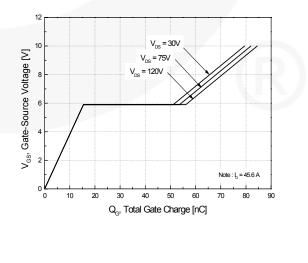


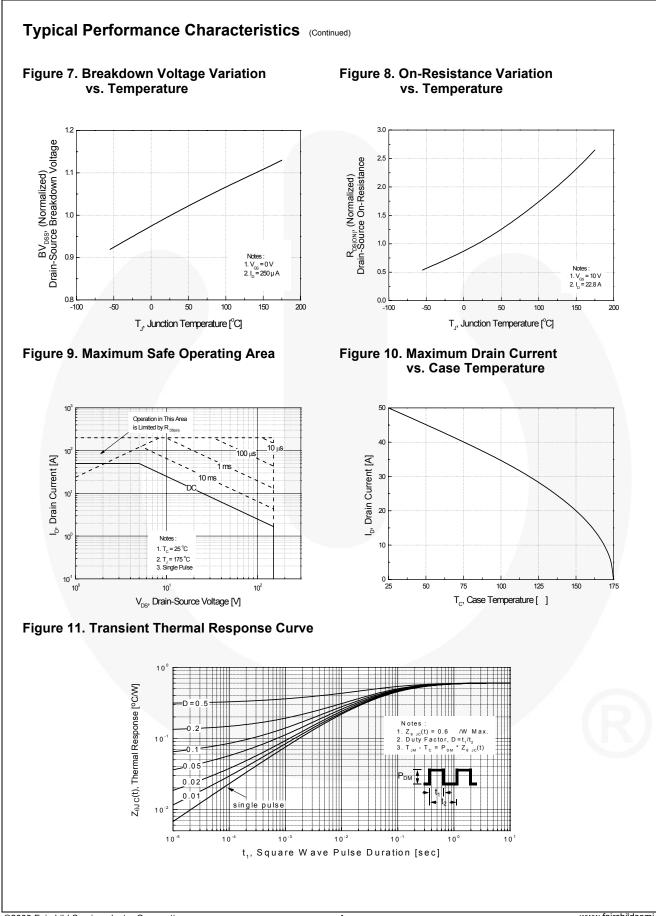






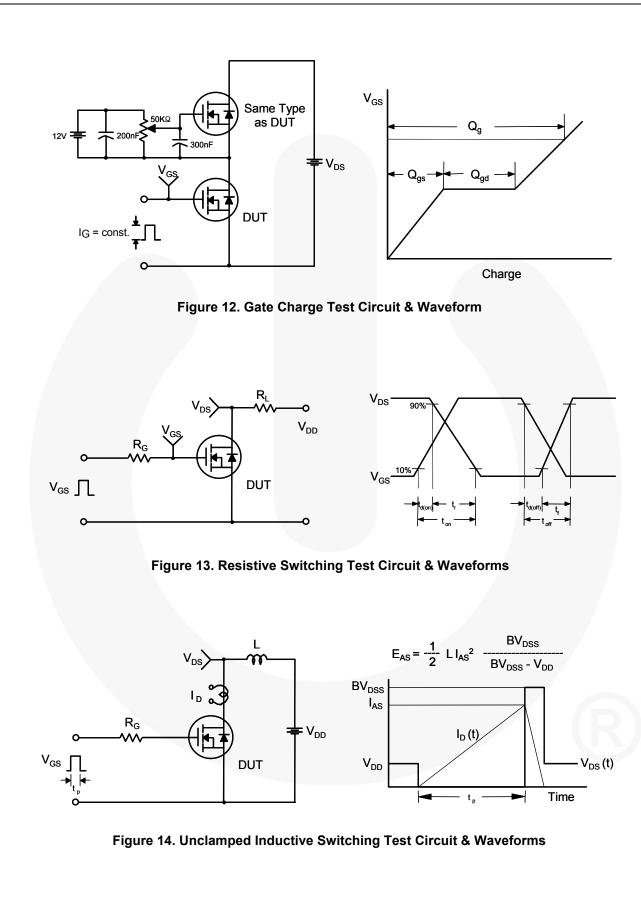


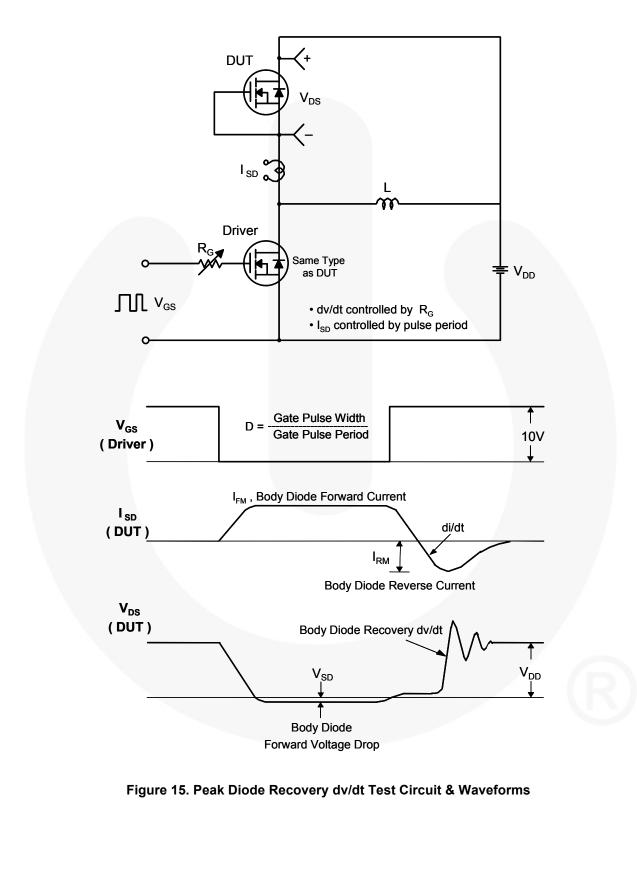


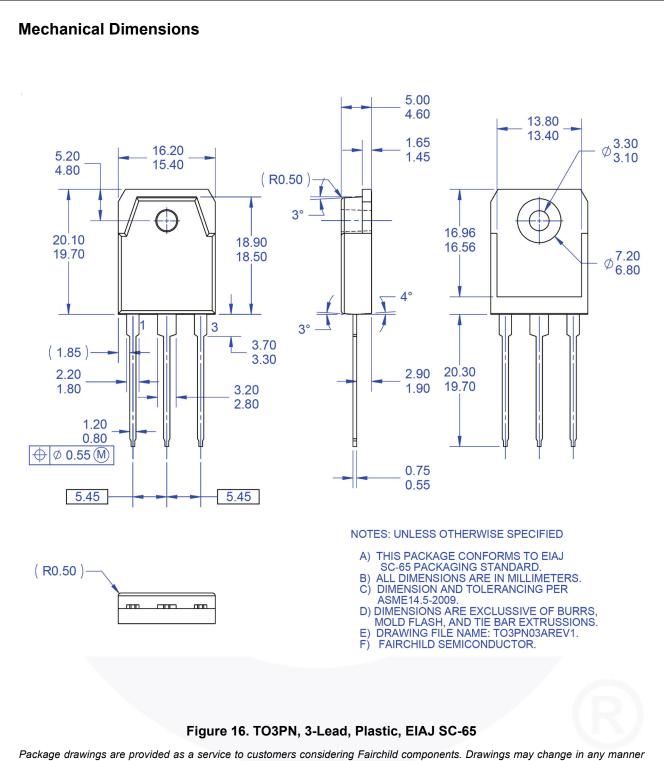


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FQA46N15 — N-Channel QFET[®] MOSFET







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FQA46N15 — N-Channel QFET[®] MOSFET



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